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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1536
Number of Logic Elements/Cells	6912
Total RAM Bits	65536
Number of I/O	260
Number of Gates	322970
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	352-LBGA Exposed Pad, Metal
Supplier Device Package	352-MBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcv300-4bg352i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Virtex Architecture

Virtex devices feature a flexible, regular architecture that comprises an array of configurable logic blocks (CLBs) surrounded by programmable input/output blocks (IOBs), all interconnected by a rich hierarchy of fast, versatile routing resources. The abundance of routing resources permits the Virtex family to accommodate even the largest and most complex designs.

Virtex FPGAs are SRAM-based, and are customized by loading configuration data into internal memory cells. In some modes, the FPGA reads its own configuration data from an external PROM (master serial mode). Otherwise, the configuration data is written into the FPGA (Select-MAPTM, slave serial, and JTAG modes).

The standard Xilinx Foundation™ and Alliance Series™ Development systems deliver complete design support for Virtex, covering every aspect from behavioral and schematic entry, through simulation, automatic design translation and implementation, to the creation, downloading, and readback of a configuration bit stream.

Higher Performance

Virtex devices provide better performance than previous generations of FPGA. Designs can achieve synchronous system clock rates up to 200 MHz including I/O. Virtex inputs and outputs comply fully with PCI specifications, and interfaces can be implemented that operate at 33 MHz or 66 MHz. Additionally, Virtex supports the hot-swapping requirements of Compact PCI.

Xilinx thoroughly benchmarked the Virtex family. While performance is design-dependent, many designs operated internally at speeds in excess of 100 MHz and can achieve 200 MHz. Table 2 shows performance data for representative circuits, using worst-case timing parameters.

Table 2: Performance for Common Circuit Functions

Function	Bits	Virtex -6
Register-to-Register		
Adder	16	5.0 ns
Audei	64	7.2 ns
Pipelined Multiplier	8 x 8	5.1 ns
	16 x 16	6.0 ns
Address Decoder	16	4.4 ns
	64	6.4 ns
16:1 Multiplexer		5.4 ns
Parity Tree	9	4.1 ns
	18	5.0 ns
	36	6.9 ns
Chip-to-Chip		
HSTL Class IV		200 MHz
LVTTL,16mA, fast slew		180 MHz



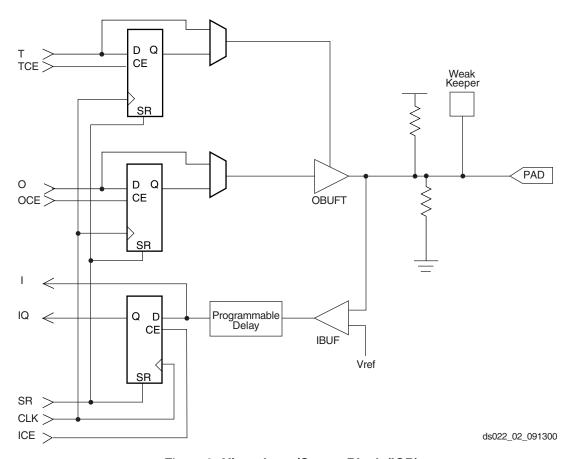


Figure 2: Virtex Input/Output Block (IOB)

Table 1: Supported Select I/O Standards

I/O Standard	Input Reference Voltage (V _{REF})	Output Source Voltage (V _{CCO})	Board Termination Voltage (V _{TT})	5 V Tolerant
LVTTL 2 – 24 mA	N/A	3.3	N/A	Yes
LVCMOS2	N/A	2.5	N/A	Yes
PCI, 5 V	N/A	3.3	N/A	Yes
PCI, 3.3 V	N/A	3.3	N/A	No
GTL	0.8	N/A	1.2	No
GTL+	1.0	N/A	1.5	No
HSTL Class I	0.75	1.5	0.75	No
HSTL Class III	0.9	1.5	1.5	No
HSTL Class IV	0.9	1.5	1.5	No
SSTL3 Class I &II	1.5	3.3	1.5	No
SSTL2 Class I & II	1.25	2.5	1.25	No
CTT	1.5	3.3	1.5	No
AGP	1.32	3.3	N/A	No



Each block SelectRAM cell, as illustrated in Figure 6, is a fully synchronous dual-ported 4096-bit RAM with independent control signals for each port. The data widths of the two ports can be configured independently, providing built-in bus-width conversion.

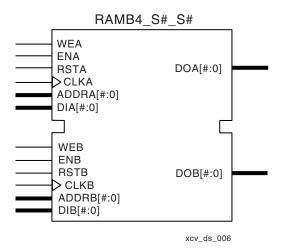


Figure 6: Dual-Port Block SelectRAM

Table 4 shows the depth and width aspect ratios for the block SelectRAM.

Table 4: Block SelectRAM Port Aspect Ratios

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

The Virtex block SelectRAM also includes dedicated routing to provide an efficient interface with both CLBs and other block SelectRAMs. Refer to XAPP130 for block SelectRAM timing waveforms.

Programmable Routing Matrix

It is the longest delay path that limits the speed of any worst-case design. Consequently, the Virtex routing architecture and its place-and-route software were defined in a single optimization process. This joint optimization minimizes long-path delays, and consequently, yields the best system performance.

The joint optimization also reduces design compilation times because the architecture is software-friendly. Design cycles are correspondingly reduced due to shorter design iteration times.

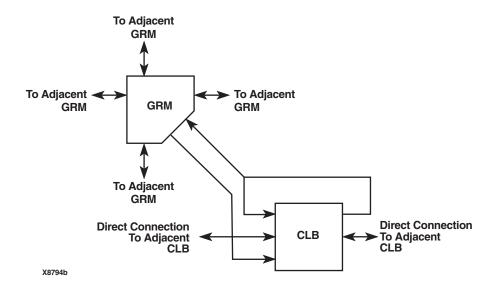


Figure 7: Virtex Local Routing

Local Routing

The VersaBlock provides local routing resources, as shown in Figure 7, providing the following three types of connections.

- Interconnections among the LUTs, flip-flops, and GRM
- Internal CLB feedback paths that provide high-speed connections to LUTs within the same CLB, chaining them together with minimal routing delay
- Direct paths that provide high-speed connections between horizontally adjacent CLBs, eliminating the delay of the GRM.



General Purpose Routing

Most Virtex signals are routed on the general purpose routing, and consequently, the majority of interconnect resources are associated with this level of the routing hierarchy. The general routing resources are located in horizontal and vertical routing channels associated with the rows and columns CLBs. The general-purpose routing resources are listed below.

- Adjacent to each CLB is a General Routing Matrix (GRM). The GRM is the switch matrix through which horizontal and vertical routing resources connect, and is also the means by which the CLB gains access to the general purpose routing.
- 24 single-length lines route GRM signals to adjacent GRMs in each of the four directions.
- 12 buffered Hex lines route GRM signals to another GRMs six-blocks away in each one of the four directions. Organized in a staggered pattern, Hex lines can be driven only at their endpoints. Hex-line signals can be accessed either at the endpoints or at the midpoint (three blocks from the source). One third of the Hex lines are bidirectional, while the remaining ones are uni-directional.

 12 Longlines are buffered, bidirectional wires that distribute signals across the device quickly and efficiently. Vertical Longlines span the full height of the device, and horizontal ones span the full width of the device.

I/O Routing

Virtex devices have additional routing resources around their periphery that form an interface between the CLB array and the IOBs. This additional routing, called the VersaRing, facilitates pin-swapping and pin-locking, such that logic redesigns can adapt to existing PCB layouts. Time-to-market is reduced, since PCBs and other system components can be manufactured while the logic design is still in progress.

Dedicated Routing

Some classes of signal require dedicated routing resources to maximize performance. In the Virtex architecture, dedicated routing resources are provided for two classes of signal.

- Horizontal routing resources are provided for on-chip 3-state busses. Four partitionable bus lines are provided per CLB row, permitting multiple busses within a row, as shown in Figure 8.
- Two dedicated nets per CLB propagate carry signals vertically to the adjacent CLB.

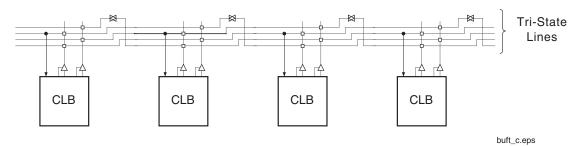


Figure 8: BUFT Connections to Dedicated Horizontal Bus Lines

Global Routing

Global Routing resources distribute clocks and other signals with very high fanout throughout the device. Virtex devices include two tiers of global routing resources referred to as primary global and secondary local clock routing resources.

• The primary global routing resources are four dedicated global nets with dedicated input pins that are designed to distribute high-fanout clock signals with minimal skew. Each global clock net can drive all CLB, IOB, and block RAM clock pins. The primary global nets can only be driven by global buffers. There are four global buffers, one for each global net. The secondary local clock routing resources consist of 24 backbone lines, 12 across the top of the chip and 12 across bottom. From these lines, up to 12 unique signals per column can be distributed via the 12 longlines in the column. These secondary resources are more flexible than the primary resources since they are not restricted to routing only to clock pins.

Clock Distribution

Virtex provides high-speed, low-skew clock distribution through the primary global routing resources described above. A typical clock distribution net is shown in Figure 9.

Four global buffers are provided, two at the top center of the device and two at the bottom center. These drive the four primary global nets that in turn drive any clock pin.



Four dedicated clock pads are provided, one adjacent to each of the global buffers. The input to the global buffer is

selected either from these pads or from signals in the general purpose routing.

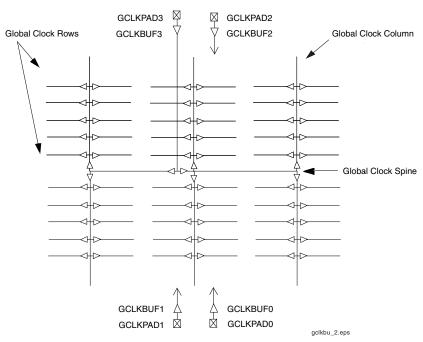


Figure 9: Global Clock Distribution Network

Delay-Locked Loop (DLL)

Associated with each global clock input buffer is a fully digital Delay-Locked Loop (DLL) that can eliminate skew between the clock input pad and internal clock-input pins throughout the device. Each DLL can drive two global clock networks. The DLL monitors the input clock and the distributed clock, and automatically adjusts a clock delay element. Clock edges reach internal flip-flops one to four clock periods after they arrive at the input. This closed-loop system effectively eliminates clock-distribution delay by ensuring that clock edges arrive at internal flip-flops in synchronism with clock edges arriving at the input.

In addition to eliminating clock-distribution delay, the DLL provides advanced control of multiple clock domains. The DLL provides four quadrature phases of the source clock, can double the clock, or divide the clock by 1.5, 2, 2.5, 3, 4, 5, 8, or 16.

The DLL also operates as a clock mirror. By driving the output from a DLL off-chip and then back on again, the DLL can be used to de-skew a board level clock among multiple Virtex devices.

In order to guarantee that the system clock is operating correctly prior to the FPGA starting up after configuration, the DLL can delay the completion of the configuration process until after it has achieved lock.

See **DLL Timing Parameters**, page 21 of Module 3, for frequency range information.

Boundary Scan

Virtex devices support all the mandatory boundary-scan instructions specified in the IEEE standard 1149.1. A Test Access Port (TAP) and registers are provided that implement the EXTEST, INTEST, SAMPLE/PRELOAD, BYPASS, IDCODE, USERCODE, and HIGHZ instructions. The TAP also supports two internal scan chains and configuration/readback of the device.The TAP uses dedicated package pins that always operate using LVTTL. For TDO to operate using LVTTL, the $\rm V_{CCO}$ for Bank 2 should be 3.3 V. Otherwise, TDO switches rail-to-rail between ground and $\rm V_{CCO}$.

Boundary-scan operation is independent of individual IOB configurations, and unaffected by package type. All IOBs, including un-bonded ones, are treated as independent 3-state bidirectional pins in a single scan chain. Retention of the bidirectional test capability after configuration facilitates the testing of external interconnections, provided the user design or application is turned off.

Table 5 lists the boundary-scan instructions supported in Virtex FPGAs. Internal signals can be captured during EXTEST by connecting them to un-bonded or unused IOBs. They can also be connected to the unused outputs of IOBs defined as unidirectional input pins.

Before the device is configured, all instructions except USER1 and USER2 are available. After configuration, all instructions are available. During configuration, it is recommended that those operations using the boundary-scan register (SAMPLE/PRELOAD, INTEST, EXTEST) not be performed.



In addition to the test instructions outlined above, the boundary-scan circuitry can be used to configure the FPGA, and also to read back the configuration data.

Figure 10 is a diagram of the Virtex Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

Instruction Set

The Virtex Series boundary scan instruction set also includes instructions to configure the device and read back configuration data (CFG_IN, CFG_OUT, and JSTART). The complete instruction set is coded as shown in Table 5.

Data Registers

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out, and 3-State Control. Non-IOB pins have appropriate partial bit population if input-only or output-only. Each EXTEST CAPTURED-OR state captures all In, Out, and 3-state pins.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA supports up to two additional internal scan chains that can be specified using the BSCAN macro. The macro provides two user pins (SEL1 and SEL2) which are decodes of the USER1 and USER2 instructions respectively. For these instructions, two corresponding pins (TDO1 and TDO2) allow user scan data to be shifted out of TDO.

Likewise, there are individual clock pins (DRCK1 and DRCK2) for each user register. There is a common input pin (TDI) and shared output pins that represent the state of the TAP controller (RESET, SHIFT, and UPDATE).

Bit Sequence

The order within each IOB is: In, Out, 3-State. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

From a cavity-up view of the chip (as shown in EPIC), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 11.

BSDL (Boundary Scan Description Language) files for Virtex Series devices are available on the Xilinx web site in the File Download area.

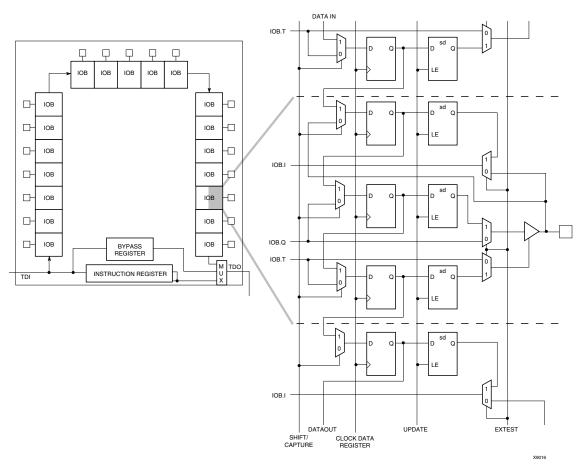


Figure 10: Virtex Series Boundary Scan Logic



Data Stream Format

Virtex devices are configured by sequentially loading frames of data. Table 11 lists the total number of bits required to configure each device. For more detailed information, see application note XAPP151 "Virtex Configuration Architecture Advanced Users Guide".

Table 11: Virtex Bit-Stream Lengths

Device	# of Configuration Bits
XCV50	559,200
XCV100	781,216
XCV150	1,040,096
XCV200	1,335,840
XCV300	1,751,808
XCV400	2,546,048
XCV600	3,607,968
XCV800	4,715,616
XCV1000	6,127,744

Readback

The configuration data stored in the Virtex configuration memory can be readback for verification. Along with the configuration data it is possible to readback the contents all flip-flops/latches, LUTRAMs, and block RAMs. This capability is used for real-time debugging.

For more detailed information, see Application Note XAPP138: *Virtex FPGA Series Configuration and Readback*, available online at www.xilinx.com.

Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99	1.2	Updated package drawings and specs.
02/99	1.3	Update of package drawings, updated specifications.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.



Virtex[™] 2.5 V Field Programmable Gate Arrays

DS003-3 (v4.0) March 1, 2013

Production Product Specification

Virtex Electrical Characteristics Definition of Terms

Electrical and switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance: These speed files are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary: These speed files are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Production: These speed files are released once enough production silicon of a particular device family member has been characterized to provide full correlation between speed files and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to Production before faster speed grades.

All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications. Contact the factory for design considerations requiring more detailed information.

Table 1 correlates the current status of each Virtex device with a corresponding speed file designation.

Table 1: Virtex Device Speed Grade Designations

	Speed Grade Designations					
Device	Advance	Preliminary	Production			
XCV50			-6, -5, -4			
XCV100			-6, -5, -4			
XCV150			-6, -5, -4			
XCV200			-6, -5, -4			
XCV300			-6, -5, -4			
XCV400			-6, -5, -4			
XCV600			-6, -5, -4			
XCV800			-6, -5, -4			
XCV1000			-6, -5, -4			

All specifications are subject to change without notice.



Power-On Power Supply Requirements

Xilinx FPGAs require a certain amount of supply current during power-on to insure proper device operation. The actual current consumed depends on the power-on ramp rate of the power supply. This is the time required to reach the nominal power supply voltage of the device⁽¹⁾ from 0 V. The current is highest at the fastest suggested ramp rate (0 V to nominal voltage in 2 ms) and is lowest at the slowest allowed ramp rate (0 V to nominal voltage in 50 ms). For more details on power supply requirements, see Application Note XAPP158 on www.xilinx.com.

Product	Description ⁽²⁾	Current Requirement ^(1,3)
Virtex Family, Commercial Grade	Minimum required current supply	500 mA
Virtex Family, Industrial Grade	Minimum required current supply	2 A

Notes:

- Ramp rate used for this specification is from 0 2.7 VDC. Peak current occurs on or near the internal power-on reset threshold of 1.0V and lasts for less than 3 ms.
- Devices are guaranteed to initialize properly with the minimum current available from the power supply as noted above.
- 3. Larger currents can result if ramp rates are forced to be faster.

DC Input and Output Levels

Values for V_{IL} and V_{IH} are recommended input voltages. Values for I_{OL} and I_{OH} are guaranteed output currents over the recommended operating conditions at the V_{OL} and V_{OH} test points. Only selected standards are tested. These are chosen to ensure that all standards meet their specifications. The selected standards are tested at minimum V_{CCO} for each standard with the respective V_{OL} and V_{OH} voltage levels shown. Other standards are sample tested.

Input/Output		V _{IL}	V _{IH} V _{OL} V _{OH}		V _{OH}	I _{OL}	I _{OH}	
Standard	V, min	V, max	V, min	V, max	V, Max	V, Max V, Min		mA
LVTTL ⁽¹⁾	- 0.5	0.8	2.0	5.5	0.4	2.4	24	-24
LVCMOS2	- 0.5	.7	1.7	5.5	0.4	1.9	12	-12
PCI, 3.3 V	- 0.5	44% V _{CCINT}	60% V _{CCINT}	V _{CCO} + 0.5	10% V _{CCO}	90% V _{CCO}	Note 2	Note 2
PCI, 5.0 V	- 0.5	0.8	2.0	5.5	0.55	2.4	Note 2	Note 2
GTL	- 0.5	V _{REF} - 0.05	V _{REF} + 0.05	3.6	0.4	n/a	40	n/a
GTL+	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.6	n/a	36	n/a
HSTL I ⁽³⁾	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	8	-8
HSTL III	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	24	-8
HSTL IV	- 0.5	V _{REF} – 0.1	V _{REF} + 0.1	3.6	0.4	V _{CCO} - 0.4	48	-8
SSTL3 I	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.6	V _{REF} + 0.6	8	-8
SSTL3 II	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.8	V _{REF} + 0.8	16	-16
SSTL2 I	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.61	V _{REF} + 0.61	7.6	-7.6
SSTL2 II	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.80	V _{REF} + 0.80	15.2	-15.2
CTT	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	V _{REF} - 0.4	V _{REF} + 0.4	8	-8
AGP	- 0.5	V _{REF} - 0.2	V _{REF} + 0.2	3.6	10% V _{CCO}	90% V _{CCO}	Note 2	Note 2

Notes:

- V_{OL} and V_{OH} for lower drive currents are sample tested.
- 2. Tested according to the relevant specifications.
- DC input and output levels for HSTL18 (HSTL I/O standard with V_{CCO} of 1.8 V) are provided in an HSTL white paper on www.xilinx.com.



Block RAM Switching Characteristics

	Speed Grade					
Description	Symbol	Min	-6	-5	-4	Units
Sequential Delays						
Clock CLK to DOUT output	T _{BCKO}	1.7	3.4	3.8	4.3	ns, max
Setup and Hold Times before/after Clock CLK ⁽¹⁾		Setu	p Time / H	old Time		
ADDR inputs	T _{BACK} /T _{BCKA}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
DIN inputs	T _{BDCK} /T _{BCKD}	0.6 / 0	1.2 / 0	1.3 / 0	1.5 / 0	ns, min
EN input	T _{BECK} /T _{BCKE}	1.3 / 0	2.6 / 0	3.0 / 0	3.4 / 0	ns, min
RST input	T _{BRCK} /T _{BCKR}	1.3 / 0	2.5 / 0	2.7 / 0	3.2 / 0	ns, min
WEN input	T _{BWCK} /T _{BCKW}	1.2 / 0	2.3 / 0	2.6 / 0	3.0 / 0	ns, min
Clock CLK						
Minimum Pulse Width, High	T _{BPWH}	0.8	1.5	1.7	2.0	ns, min
Minimum Pulse Width, Low	T _{BPWL}	0.8	1.5	1.7	2.0	ns, min
CLKA -> CLKB setup time for different ports	T _{BCCS}		3.0	3.5	4.0	ns, min

Notes:

TBUF Switching Characteristics

		Speed Grade				
Description	Symbol	Min	-6	-5	-4	Units
Combinatorial Delays						
IN input to OUT output	T _{IO}	0	0	0	0	ns, max
TRI input to OUT output high-impedance	T _{OFF}	0.05	0.09	0.10	0.11	ns, max
TRI input to valid data on OUT output	T _{ON}	0.05	0.09	0.10	0.11	ns, max

JTAG Test Access Port Switching Characteristics

	Spee			eed Grade		
Description	Symbol	-6	-5	-4	Units	
TMS and TDI Setup times before TCK	T _{TAPTCK}	4.0	4.0	4.0	ns, min	
TMS and TDI Hold times after TCK	T _{TCKTAP}	2.0	2.0	2.0	ns, min	
Output delay from clock TCK to output TDO	T _{TCKTDO}	11.0	11.0	11.0	ns, max	
Maximum TCK clock frequency	F _{TCK}	33	33	33	MHz, max	

^{1.} A Zero "0" Hold Time listing indicates no hold time or a negative hold time. Negative values can not be guaranteed "best-case", but if a "0" is listed, there is no positive hold time.



Virtex[™] 2.5 V Field Programmable Gate Arrays

DS003-4 (v4.0) March 1, 2013

Production Product Specification

Virtex Pin Definitions

Table 1: Special Purpose Pins

Pin Name	Dedicated Pin	Direction	Description	
GCK0, GCK1, GCK2, GCK3	Yes	Input	Clock input pins that connect to Global Clock Buffers. These pins become user inputs when not needed for clocks.	
M0, M1, M2	Yes	Input	Mode pins are used to specify the configuration mode.	
CCLK	Yes	Input or Output	The configuration Clock I/O pin: it is an input for SelectMAP and slave-serial modes, and output in master-serial mode. After configuration it is input only, logic level = Don't Care.	
PROGRAM	Yes	Input	Initiates a configuration sequence when asserted Low.	
DONE	Yes	Bidirectional	Indicates that configuration loading is complete, and that the start-up sequence is in progress. The output can be open drain.	
INIT	No	Bidirectional (Open-drain)	When Low, indicates that the configuration memory is being cleared. The pin becomes a user I/O after configuration.	
BUSY/ DOUT	No	Output	In SelectMAP mode, BUSY controls the rate at which configuration data is loaded. The pin becomes a user I/O after configuration unless the SelectMAP port is retained.	
			In bit-serial modes, DOUT provides header information to downstream devices in a daisy-chain. The pin becomes a user I/O after configuration.	
D0/DIN, D1, D2, D3, D4, D5, D6, D7	No	Input or Output	In SelectMAP mode, D0 - D7 are configuration data pins. These pins become user I/Os after configuration unless the SelectMAP port is retained. In bit-serial modes, DIN is the single data input. This pin becomes a user I/O after configuration.	
WRITE	No	Input	In SelectMAP mode, the active-low Write Enable signal. The pin becomes a user I/O after configuration unless the SelectMAP port is retained.	
CS	No	Input	In SelectMAP mode, the active-low Chip Select signal. The pin becomes a user I/O after configuration unless the SelectMAP port is retained.	
TDI, TDO, TMS, TCK	Yes	Mixed	Boundary-scan Test-Access-Port pins, as defined in IEEE 1149.1.	
DXN, DXP	Yes	N/A	Temperature-sensing diode pins. (Anode: DXP, cathode: DXN)	
V _{CCINT}	Yes	Input	Power-supply pins for the internal core logic.	
V _{CCO}	Yes	Input	Power-supply pins for the output drivers (subject to banking rules)	
V _{REF}	No	Input	Input threshold voltage pins. Become user I/Os when an external threshold voltage is not needed (subject to banking rules).	
GND	Yes	Input	Ground	

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Virtex Pinout Information

Pinout Tables

See www.xilinx.com for updates or additional pinout information. For convenience, Table 2, Table 3 and Table 4 list the locations of special-purpose and power-supply pins. Pins not listed are either user I/Os or not connected, depending on the device/package combination. See the Pinout Diagrams starting on page 17 for any pins not listed for a particular part/package combination.

Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages)

Pin Name	Device	CS144	TQ144	PQ/HQ240
GCK0	All	K7	90	92
GCK1	All	M7	93 89	
GCK2	All	A7	19	210
GCK3	All	A6	16	213
MO	All	M1	110	60
M1	All	L2	112	58
M2	All	N2	108	62
CCLK	All	B13	38	179
PROGRAM	All	L12	72	122
DONE	All	M12	74	120
INIT	All	L13	71	123
BUSY/DOUT	All	C11	39	178
D0/DIN	All	C12	40	177
D1	All	E10	45	167
D2	All	E12	47	163
D3	All	F11	51	156
D4	All	H12	59	145
D5	All	J13	63	138
D6	All	J11	65	134
D7	All	K10	70	124
WRITE	All	C10	32	185
CS	All	D10	33	184
TDI	All	A11	34	183
TDO	All	A12	36	181
TMS	All	B1	143	2
TCK	All	C3	2	239
V _{CCINT}	All	A9, B6, C5, G3, G12, M5, M9, N6	10, 15, 25, 57, 84, 94, 99, 126	16, 32, 43, 77, 88, 104, 137, 148, 164, 198, 214, 225



Table 2: Virtex Pinout Tables (Chip-Scale and QFP Packages) (Continued)

Pin Name	Device	CS144	TQ144	PQ/HQ240
V _{REF} , Bank 3	XCV50	H11, K12	60, 68	130, 144
(V _{REF} pins are listed	XCV100/150	+ J10	+ 66	+ 133
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 126
the required device	XCV400	N/A	N/A	+ 147
and all smaller devices listed in the same	XCV600	N/A	N/A	+ 132
package.)	XCV800	N/A	N/A	+ 140
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 4	XCV50	L8, L10	79, 87	97, 111
(V _{REF} pins are listed	XCV100/150	+ N10	+ 81	+ 108
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 115
the required device and all smaller devices	XCV400	N/A	N/A	+ 94
listed in the same	XCV600	N/A	N/A	+ 109
package.)	XCV800	N/A	N/A	+ 101
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				
V _{REF} , Bank 5	XCV50	L4, L6	96, 104	70, 84
(V _{REF} pins are listed	XCV100/150	+ N4	+ 102	+ 73
incrementally. Connect all pins listed for both	XCV200/300	N/A	N/A	+ 66
the required device	XCV400	N/A	N/A	+ 87
and all smaller devices listed in the same package.)	XCV600	N/A	N/A	+ 72
	XCV800	N/A	N/A	+ 80
Within each bank, if input reference voltage is not required, all V _{REF} pins are general I/O.				



Table 4: Virtex Pinout Tables (Fine-Pitch BGA) (Continued)

Pin Name	Device	FG256	FG456	FG676	FG680
No Connect (No-connect pins are listed incrementally. All pins listed for both the required device and all larger devices listed in the same package are no connects.)	XCV800	N/A	N/A	A2, A3, A15, A25, B1, B6, B11, B16, B21, B24, B26, C1, C2, C25, C26, F2, F6, F21, F25, L2, L25, N25, P2, T2, T25, AA2, AA6, AA21, AA25, AD1, AD2, AD25, AE1, AE3, AE6, AE11, AE14, AE16, AE21, AE24, AE26, AF2, AF24, AF25	N/A
	XCV600	N/A	N/A	same as above	N/A
	XCV400	N/A	N/A	+ A9, A10, A13, A16, A24, AC1, AC25, AE12, AE15, AF3, AF10, AF11, AF13, AF14, AF16, AF18, AF23, B4, B12, B13, B15, B17, D1, D25, H26, J1, K26, L1, M1, M25, N1, N26, P1, P26, R2, R26, T1, T26, U26, V1	N/A
	XCV300	N/A	D4, D19, W4, W19	N/A	N/A
	XCV200	N/A	+ A2, A6, A12, B11, B16, C2, D1, D18, E17, E19, G2, G22, L2, L19, M2, M21, R3, R20, U3, U18, Y22, AA1, AA3, AA11, AA16, AB7, AB12, AB21,	N/A	N/A
	XCV150	N/A	+ A13, A14, C8, C9, E13, F11, H21, J1, J4, K2, K18, K19, M17, N1, P1, P5, P22, R22, W13, W15, AA9, AA10, AB8, AB14	N/A	N/A



BG256 Pin Function Diagram

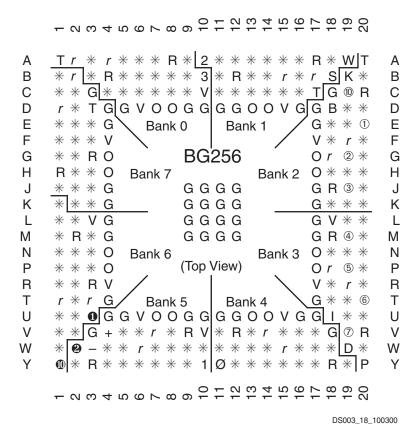
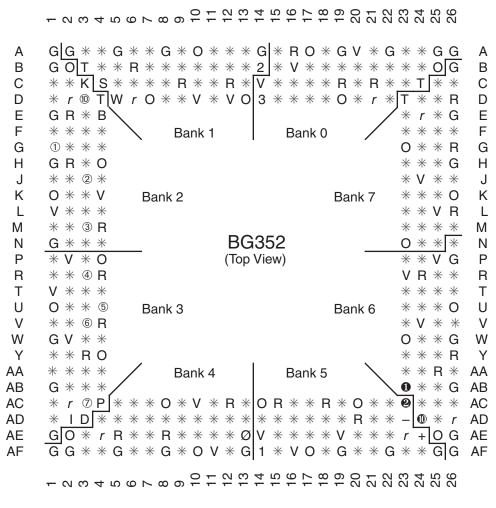


Figure 4: BG256 Pin Function Diagram



BG352 Pin Function Diagram

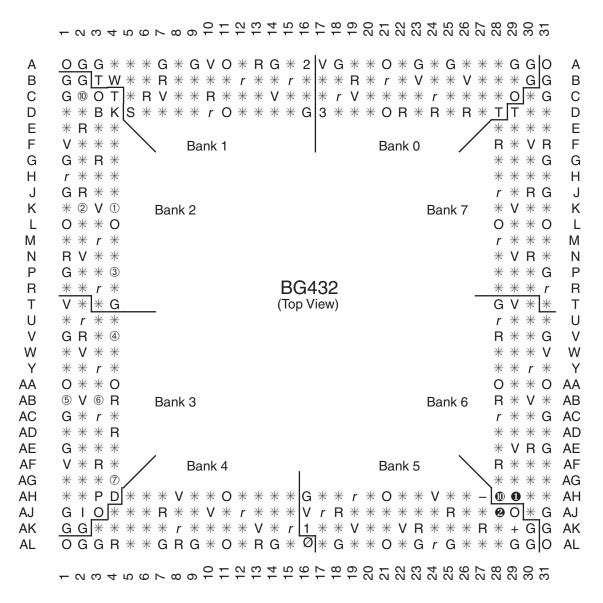


DS003_19_100600

Figure 5: BG352 Pin Function Diagram



BG432 Pin Function Diagram



DS003_21_100300

Figure 6: BG432 Pin Function Diagram



FG256 Pin Function Diagram

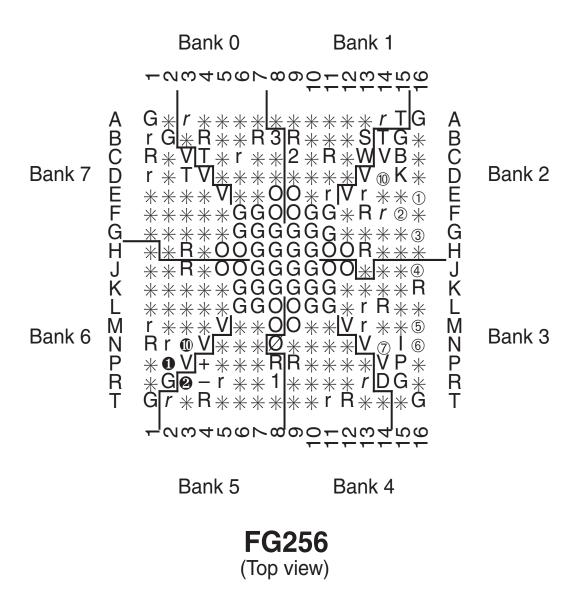
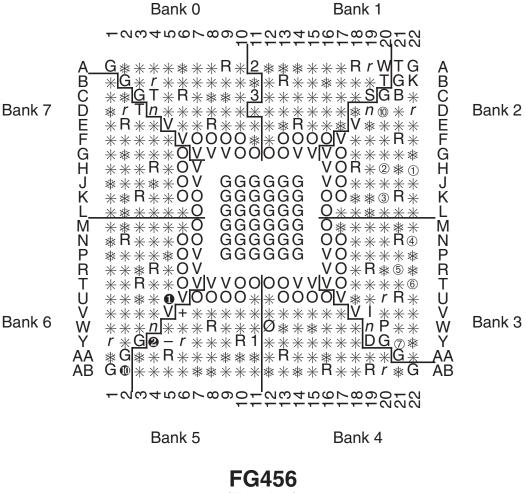


Figure 8: FG256 Pin Function Diagram



FG456 Pin Function Diagram



(Top view)

Figure 9: FG456 Pin Function Diagram

Notes:

Packages FG456 and FG676 are layout compatible.



Revision History

Date	Version	Revision
11/98	1.0	Initial Xilinx release.
01/99-02/99	1.2-1.3	Both versions updated package drawings and specs.
05/99	1.4	Addition of package drawings and specifications.
05/99	1.5	Replaced FG 676 & FG680 package drawings.
07/99	1.6	Changed Boundary Scan Information and changed Figure 11, Boundary Scan Bit Sequence. Updated IOB Input & Output delays. Added Capacitance info for different I/O Standards. Added 5 V tolerant information. Added DLL Parameters and waveforms and new Pin-to-pin Input and Output Parameter tables for Global Clock Input to Output and Setup and Hold. Changed Configuration Information including Figures 12, 14, 17 & 19. Added device-dependent listings for quiescent currents ICCINTQ and ICCOQ. Updated IOB Input and Output Delays based on default standard of LVTTL, 12 mA, Fast Slew Rate. Added IOB Input Switching Characteristics Standard Adjustments.
09/99	1.7	Speed grade update to preliminary status, Power-on specification and Clock-to-Out Minimums additions, "0" hold time listing explanation, quiescent current listing update, and Figure 6 ADDRA input label correction. Added T _{IJITCC} parameter, changed T _{OJIT} to T _{OPHASE} .
01/00	1.8	Update to speed.txt file 1.96. Corrections for CRs 111036,111137, 112697, 115479, 117153, 117154, and 117612. Modified notes for Recommended Operating Conditions (voltage and temperature). Changed Bank information for V _{CCO} in CS144 package on p.43.
01/00	1.9	Updated DLL Jitter Parameter table and waveforms, added Delay Measurement Methodology table for different I/O standards, changed buffered Hex line info and Input/Output Timing measurement notes.
03/00	2.0	New TBCKO values; corrected FG680 package connection drawing; new note about status of CCLK pin after configuration.
05/00	2.1	Modified "Pins not listed" statement. Speed grade update to Final status.
05/00	2.2	Modified Table 18.
09/00	2.3	 Added XCV400 values to table under Minimum Clock-to-Out for Virtex Devices. Corrected Units column in table under IOB Input Switching Characteristics. Added values to table under CLB SelectRAM Switching Characteristics.
10/00	2.4	 Corrected pinout info for devices in the BG256, BG432, and BG560 pkgs in Table 18. Corrected BG256 Pin Function Diagram.
04/02/01	2.5	 Revised minimums for Global Clock Set-Up and Hold for LVTTL Standard, with DLL. Converted file to modularized format. See section Virtex Data Sheet, below.
04/19/01	2.6	Corrected pinout information for FG676 device in Table 4. (Added AB22 pin.)
07/19/01	2.7	 Clarified V_{CCINT} pinout information and added AE19 pin for BG352 devices in Table 3. Changed pinouts listed for BG352 XCV400 devices in banks 0 thru 7.
07/19/02	2.8	Changed pinouts listed for GND in TQ144 devices (see Table 2).
03/01/13	4.0	The products listed in this data sheet are obsolete. See XCN10016 for further information.

Virtex Data Sheet

The Virtex Data Sheet contains the following modules:

- DS003-1, Virtex 2.5V FPGAs: Introduction and Ordering Information (Module 1)
- DS003-2, Virtex 2.5V FPGAs: Functional Description (Module 2)

- DS003-3, Virtex 2.5V FPGAs: DC and Switching Characteristics (Module 3)
- DS003-4, Virtex 2.5V FPGAs: Pinout Tables (Module 4)